

# **AT-T2000 Series Automatic Test System**

AT-T2000 adopts hardware modular embedded framework structure. Because of the variety of APM power source, E-load and home-made board cards, it could provide a variety of hardware options according to the requirements, to facilitate customer cost control. It provides flexibility and expandability to the system. At the meanwhile, the system is compatible with various brands model of power analyzer, digital oscilloscope, multimeter.

# ► Range of application

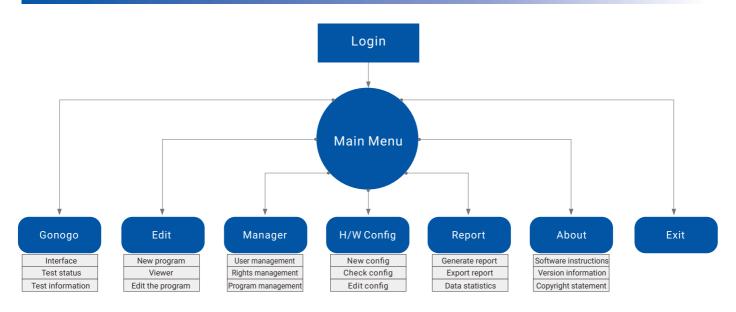
AC source, DC source, DC E-load, AC/DC power module, DC/DC power module, adapter, charger, LED power source, telecom power source.



#### **Features**

- Graphic interface, simple and clear.
- Standard test item, available to expand elastically
- Module design, easy to maintain
- High measurement accuracy, stable system operation
- Support single or multi channel parallel test
- Multilevel managing privileges setting function
- User privileges setting function
- Open software edition platform, available to edit and modify the test program

# **Software Architecture and Specifications**





# Description of Module Functions (as shown in the figure above)

- Login: Login to the main menu of the software with the correct user name and password
- GO/NOGO(test execution): the main test interface, test status and results display screen, which can be used for some corresponding operations in the test process, and the test information can be set, such as work order, etc., which will be reflected in the test report
- Edit: add and edit the test program, that is, users select test items according to the required specifications and enter corresponding parameters
- H/W(hardware): match the test hardware as required, set the information and save it as a file, then select the corresponding hardware configuration for the required test products in combination with the Edit module
- Management: software user management(add, edit or delete); user rights management; test procedures management(release, import or export delete, etc.)
- About: view information about the software, such as version, copyright, etc
- Exit: select to exit from the test software

### Software Interface Diagram

Clear software function modular division and simple interface, it is easy for user to use.

# Logo in interface

Support Chinese/English operation interface



# Guidance interface

Quick switch to target interface





# Test Interface

It could directly insert edited test program for test. Besides final test result highlighted display, test result of each test item will display with different color for user to find out the abnormal item.



# Edit Interface

Test program is edited in this interface. It could directly use in test interface after saving it. Besides built-in test item, user could set new test item based on defined VI program of system to satisfy different test requirement.



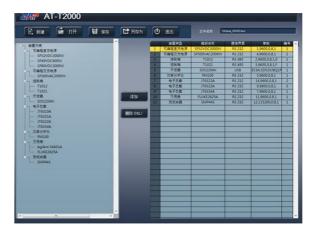
# Management Interface

Set user-permission



# H/W Configuration Interface

User could select equipment to configure system to realize automtic test.





### **Access to Test Report**

Test report could automatically upload to designated spot of server according to different test product and test result.

|    | A   | В                            | C                     | D        | Е     | F                 | G            |
|----|---|------------------------------|-----------------------|----------|-------|-------------------|--------------|
|    |   |                              | Certificate of Testin | g Report |       |                   |              |
| 1  |   |                              |                       |          |       |                   |              |
| 2  | Manufacturer  | XXXX                         |                       |          |       | Model:            | DC60-5       |
| 3  | Serial Number:  | 0149482027000050             |                       |          |       | AVRversion:       | 100.0.2      |
| 4  | Cal Date/Time:  | 2020/7/2 08:30               |                       |          |       | STM32version:     | 100.0.4      |
| 5  | Test Result:  | PASS                         |                       |          |       | MAC:              | NA           |
| 6  |   |                              |                       |          |       |                   |              |
| 7  | APM recommended calibration interval of this instument is 12 months and start couted from the date of the instrment activated into service, |                              |                       |          |       |                   |              |
| 8  |   |                              |                       |          |       |                   |              |
| 9  | Instrument Condition  | on: Meets all specifications |                       |          |       | Calibration Site: | PPS-DC-ATE   |
| 0  |   |                              |                       |          |       |                   |              |
| 11 | Calibration Equipment Used:   |                              |                       |          |       |                   |              |
| 12 | Item  | Mfg/Model Type               | Serial No.            |          |       | Cal.Date          | Cal.Due Date |
| 3  | 1   | RIGOL DS1204B                | DS1BA171300029        |          |       | 2018/11/5         | 2019/11/4    |
| 4  | 2   | YOKOGAWA WT210               | 91M935715             |          |       | 2018/11/5         | 2019/11/4    |
| 5  | 3   | FLUKE 8808A                  | 1238033               |          |       | 2018/11/5         | 2019/11/4    |
| 6  | 4   | AITEK AWE2101                | 120401054             |          |       | 2018/11/5         | 2019/11/4    |
| 7  | 6   | RIGOL DM3068                 | DM30161850131         |          |       | 2018/11/5         | 2019/11/4    |
| 8  |   |                              |                       |          |       |                   |              |
| 19 | Item  | Step                         | Description           | Min      | Value | Max               | Result       |
| Ø  | Testing Index   |                              |                       |          |       |                   |              |
| 1  |   | A0                           | FCT/ATE Testing       | 1        | OK    | 1                 | PASS         |
| 2  |   | A1                           | HI-POT Testing        | 1        | OK    | 1                 | PASS         |
| 3  |   | A2                           | Vibration Testing     | 1        | OK    | 1                 | PASS         |
| 4  | 7.  | A3                           | BRUN-IN Testing       | 1        | OK    | 1                 | PASS         |
| 25 |   | A4                           | QA Testing            | 1        | OK    | 1                 | PASS         |
| 26 | selow is Testing Da   | ita                          |                       |          |       |                   |              |
| 27 |   | 12                           | Master_Slaver_Test    |          |       |                   |              |
| 28 |   |                              |                       | 1        | OK    | 1                 | PASS         |

### **Testing Items**

ATE SYSTEM could realize below 7 test items.

#### **Product information**

- SN/MAC information input
- Product information comparison

#### **Stability Test**

- Line regulation test
- Load regulation test

### **Protection characteristic test**

- Short circuit protection test
- Over voltage protection test
- Over load protection test
- Over power protection test

#### Input characteristic test

- Input current RMS test
- Input power factor test
- Input power disturbance test
- Input frequency fluctuation test
- Input power test

#### **Timing and Transient Characteristics**

- Startup time test
- Rise time test
- Shutdown time test
- Fall time test

#### **Control characteristic test**

- RS232 read and write
- RS485 read and write
- USB read and write
- LAN read and write
- GPIB read and write

### **Output characteristic test**

- Output voltage/current/power accuracy test
- Output voltage ripple test
- Output efficiency test
- Dynamic mode test



### **AC-DC/DC-DC Power Module Test System**



This system is applicable in AC-DC/DC-DC power module test.

AC-DC/DC-DC module power is widely used in military, communication equipment, automotive electronics and aerospace. Standard test item of test system matching with external test fixtures could realize automatic test. It could avoid error that may be caused by repeated test manually and improve test efficiency significantly.

# **Medium/Low Power DC Power Test System**



The test system is suitable for the medium/low power DC power supply test. Test capacity: voltage  $0 \sim 800 \text{VDC}$ , current  $0 \sim 200 \text{A}$ ,  $0 \sim 4000 \text{W}$ , expandable; In addition to the test items that implement the above standards, customized function expansion can be realized according to customer needs.

# Medium/low power AC Power Supply Test System



This test system is suitable for the medium/low power AC power supply test. Test capacity: voltage  $0\sim300\text{VDC}$ , current  $0\sim46\text{A}$ ,  $0\sim5000\text{W}$ , expandable; In addition to the test items that implement the above standards, customized function expansion can be realized according to customer needs.



### **DC Electronic Load Test System**

The test system is suitable for DC Electronic Load. Test capacity: voltage  $0\sim1200$ VDC, current  $0\sim3000$ A,  $0\sim300$ kW, expandable; In addition to the test items that implement the above standards, customized function expansion can be realized according to customer needs.



### **High-power DC Power Supply Test System**

The test system is suitable for the high-power DC power supply test. Test capacity: voltage  $0\sim2250\text{VDC}$ , current  $0\sim3000\text{A}$ ,  $0\sim300\text{kW}$ , expandable; In addition to the test items that implement the above standards, customized function expansion can be realized according to customer needs.



Welcome to contact regional sales for more detail information.